# International Rectifier

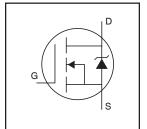
# AUIRFS4310 AUIRFSL4310

#### **Features**

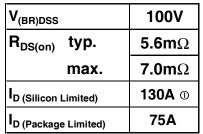
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

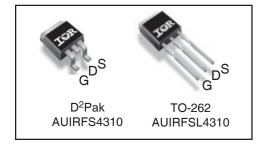
## **Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



# HEXFET® Power MOSFET





G	D	S
Gate	Drain	Source

## **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T<sub>A</sub>) is 25°C, unless otherwise specified.

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	130①	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	92①	A
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, VGS @ 10V (Package Limited)	75	7 ^
I <sub>DM</sub>	Pulsed Drain Current ②	550	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	300	W
	Linear Derating Factor	2.0	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally limited) 3	980	mJ
I <sub>AR</sub>	Avalanche Current ②	See Fig. 14, 15, 22a, 22b,	А
E <sub>AR</sub>	Repetitive Avalanche Energy		mJ
dV/dt	Peak Diode Recovery @	14	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		_
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10lb·in (1.1N·m)	

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		0.50	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ®		40	C/VV

HEXFET® is a registered trademark of International Rectifier.

<sup>\*</sup>Qualification standards can be found at http://www.irf.com/

## Static Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.064		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>②</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		5.6	7.0	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A ⑤
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Transconductance	160			S	$V_{DS} = 50V, I_{D} = 75A$
$R_{G}$	Gate Input Resistance		1.4		Ω	f = 1MHz, open drain
I <sub>DSS</sub>	Drain-to-Source Leakage Current			20		$V_{DS} = 100V, V_{GS} = 0V$
				250	μΑ	$V_{DS} = 100V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I <sub>GSS</sub>	Gate-to-Source Forward Leakage			200	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage			-200	I IIA	V <sub>GS</sub> = -20V

## Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	<u> </u>		_		· · · ·	• ""
	Parameter	Min.	Тур.	wax.	Units	Conditions
$Q_g$	Total Gate Charge		170	250		$I_D = 75A$
$Q_{gs}$	Gate-to-Source Charge		46		nC	$V_{DS} = 80V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		62			V <sub>GS</sub> = 10V ⑤
t <sub>d(on)</sub>	Turn-On Delay Time		26			$V_{DD} = 65V$
t <sub>r</sub>	Rise Time		110		,,	$I_D = 75A$
t <sub>d(off)</sub>	Turn-Off Delay Time		68		ns	$R_G = 2.6\Omega$
t <sub>f</sub>	Fall Time		78			V <sub>GS</sub> = 10V ⑤
C <sub>iss</sub>	Input Capacitance		7670			$V_{GS} = 0V$
C <sub>oss</sub>	Output Capacitance		540			$V_{DS} = 50V$
C <sub>rss</sub>	Reverse Transfer Capacitance		280		pF	f = 1.0MHz
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related)		650			$V_{GS} = 0V$ , $V_{DS} = 0V$ to $80V ②$ , See Fig.11
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)		720.1			$V_{GS} = 0V$ , $V_{DS} = 0V$ to $80V$ $©$ , See Fig. 5

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>s</sub>	Continuous Source Current			130①		MOSFET symbol
	(Body Diode)			1300	Α	showing the
I <sub>SM</sub>	Pulsed Source Current			550		integral reverse
	(Body Diode) ②⑦			330		p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V $ §
t <sub>rr</sub>	Reverse Recovery Time		45	68		$T_J = 25^{\circ}C$ $V_R = 85V$ ,
			55	83	ns	$T_{\rm J} = 125^{\circ}{\rm C}$ $I_{\rm F} = 75{\rm A}$
$Q_{rr}$	Reverse Recovery Charge		82	120	nC	$T_J = 25^{\circ}C$ di/dt = 100A/ $\mu$ s $\odot$
			120	180		$T_J = 125$ °C
I <sub>RRM</sub>	Reverse Recovery Current		3.3		Α	$T_J = 25^{\circ}C$
t <sub>on</sub>	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

#### Notes:

- Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ Limited by  $T_{Jmax}$ , starting  $T_J$  = 25°C, L = 0.35mH  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = 75A,  $V_{GS}$  =10V. Part not recommended for use above this value.
- $\textcircled{4} \ \ I_{SD} \leq 75 A, \ di/dt \leq 550 A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_{J} \leq 175^{\circ}C.$
- ⑤ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .

- $^{\circ}$  C<sub>oss</sub> eff. (TR) is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- $\ \, \ \, \ \,$   $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}.$
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- <sup>®</sup> R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C.

# Qualification Information<sup>†</sup>

			Automotive			
Qualification Level		(per AEC-Q101) <sup>††</sup>				
		Comments: This part number(s) passed Automotive qualification. IR's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture Sensitivity Level		TO-262	N/A			
Woisture Serisitiv	vity Level	D <sup>2</sup> PAK MSL1				
	Machine Model	Class M4(425V)				
		(per AEC-Q101-002)				
500	Human Body Model	Class H2(4000V)				
ESD			(per AEC-Q101-001)			
	Charged Device	Class C4 (1000V)				
Model		(per AEC-Q101-005)				
RoHS Compliant		Yes				

<sup>†</sup> Qualification standards can be found at International Rectifier's web site: http://www.irf.com/

<sup>††</sup> Exceptions to AEC-Q101 requirements are noted in the qualification report.

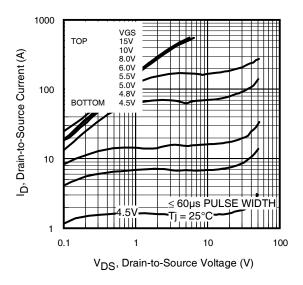


Fig 1. Typical Output Characteristics

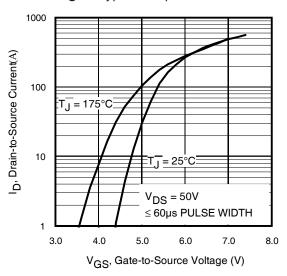


Fig 3. Typical Transfer Characteristics

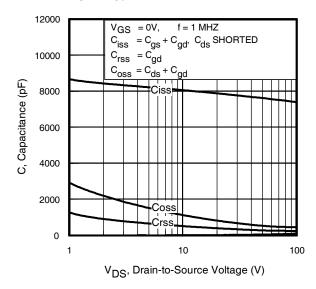


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

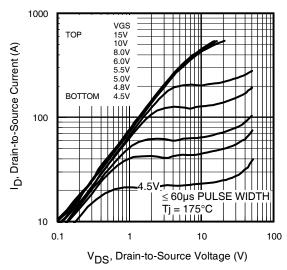


Fig 2. Typical Output Characteristics

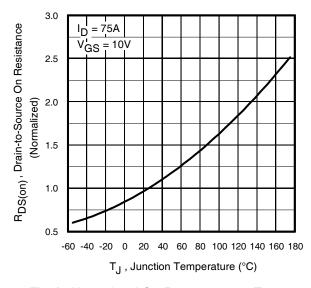
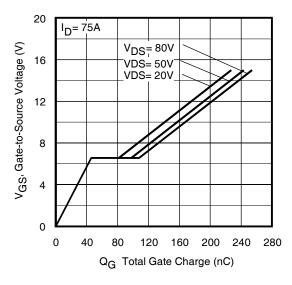
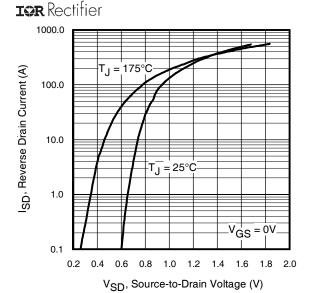


Fig 4. Normalized On-Resistance vs. Temperature



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage www.irf.com



**Fig 7.** Typical Source-Drain Diode Forward Voltage

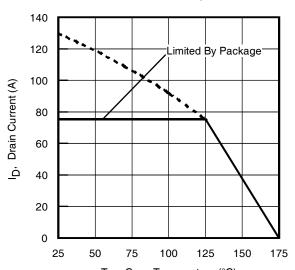
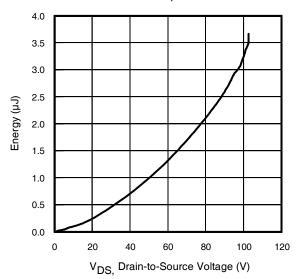


Fig 9. Case Temperature (°C)
Maximum Drain Current vs.
Case Temperature



**Fig 11.** Typical C<sub>OSS</sub> Stored Energy

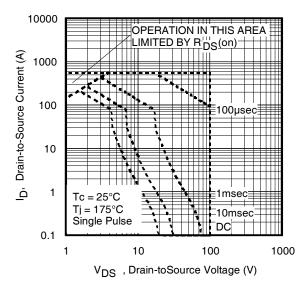


Fig 8. Maximum Safe Operating Area

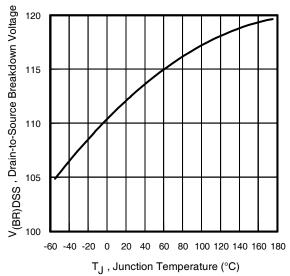


Fig 10. Drain-to-Source Breakdown Voltage

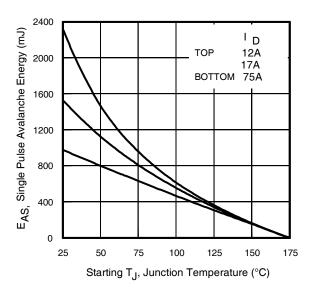


Fig 12. Maximum Avalanche Energy Vs. DrainCurrent

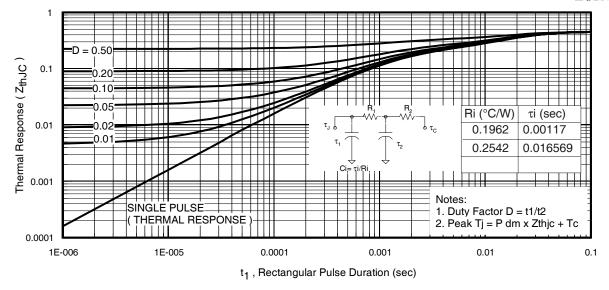


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

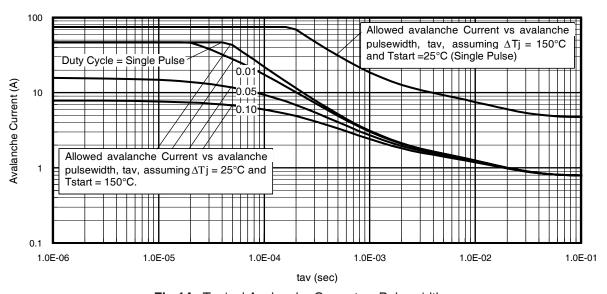


Fig 14. Typical Avalanche Current vs. Pulsewidth

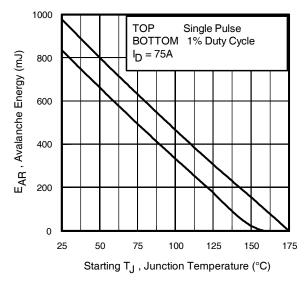


Fig 15. Maximum Avalanche Energy vs. Temperature

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# Notes on Repetitive Avalanche Curves , Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{\rm jmax}$ . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as neither  $T_{jmax}$  nor  $I_{av\ (max)}$  is exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 22a, 22b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 14, 15).
  - t<sub>av</sub> = Average time in avalanche.
  - D = Duty cycle in avalanche = tav ·f
  - $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{aV}) = \triangle T / \; Z_{thJC} \\ I_{av} &= 2\triangle T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

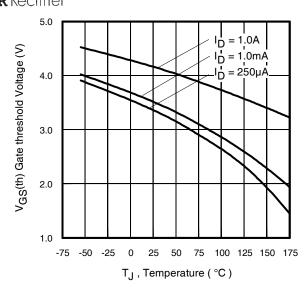


Fig 16. Threshold Voltage Vs. Temperature

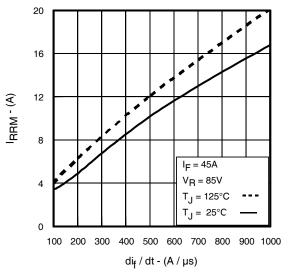


Fig. 18 - Typical Recovery Current vs. dif/dt

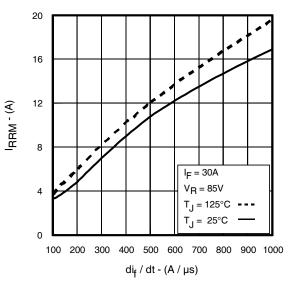


Fig. 17 - Typical Recovery Current vs. di<sub>f</sub>/dt

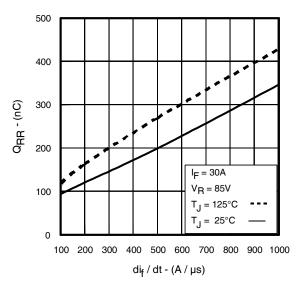


Fig. 19 - Typical Stored Charge vs. dif/dt

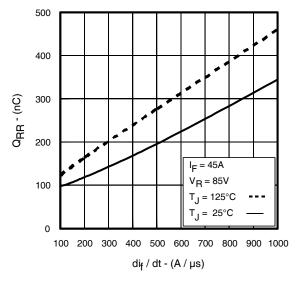


Fig. 20 - Typical Stored Charge vs. dif/dt

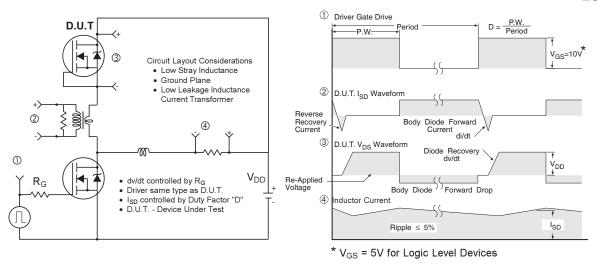


Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

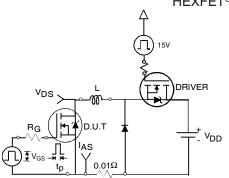


Fig 22a. Unclamped Inductive Test Circuit

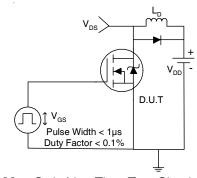


Fig 23a. Switching Time Test Circuit

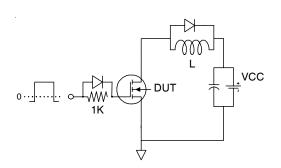


Fig 24a. Gate Charge Test Circuit

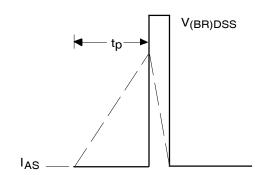


Fig 22b. Unclamped Inductive Waveforms

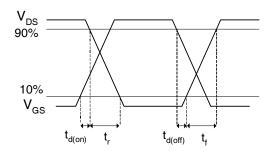


Fig 23b. Switching Time Waveforms

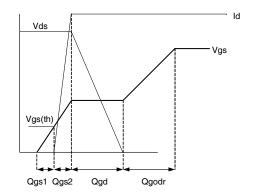
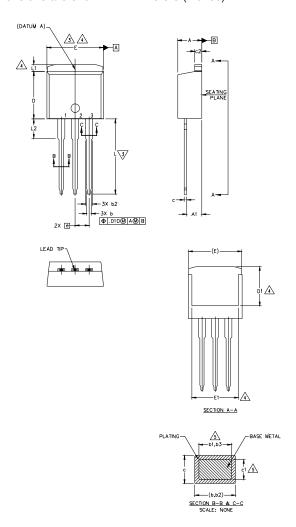


Fig 24b. Gate Charge Waveform

# TO-262 Package Outline

Dimensions are shown in millimeters (inches)



#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
  - 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

S Y M		N			
B	MILLIM	MILLIMETERS		HES	N O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	2.03	3.02	.080	.119	
ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1,14	1,73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0,38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	-	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245		4
e	2.54	BSC	.100 BSC		
L	13.46	14,10	.530	,555	
L1	-	1.65	-	.065	4
L2	3.56	3.71	.140	.146	

#### LEAD ASSIGNMENTS

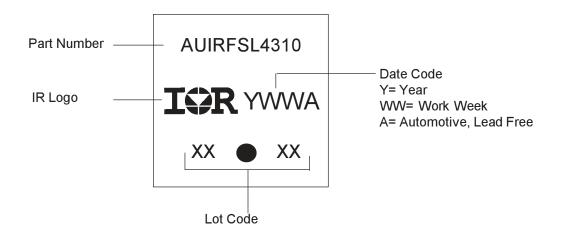
#### <u>HEXFET</u>

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

#### IGBTs, CoPACK

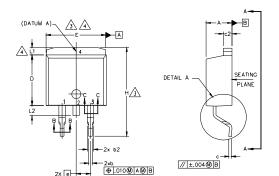
- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

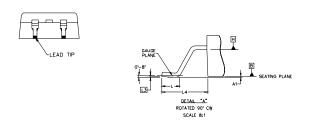
# TO-262 Part Marking Information

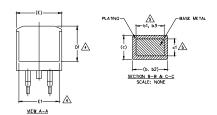


# D<sup>2</sup>Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)







#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND 61 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S			N		
M B O	MILLIM	ETERS	INCHES		O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
c1	0.38	0,58	.015	.023	5
c2	1,14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6,86	-	.270		4
E	9.65	10.67	.380	.420	3,4
E1	6.22	245			4
е	2.54	BSC	.100	BSC	
Н	14,61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	4
L2	1.27	1.78	-	.070	
L3	0.25	BSC	.010	,010 BSC	
L4	4.78	5.28	.188	.208	

## LEAD ASSIGNMENTS

## <u>HEXFET</u>

1.- GATE 2, 4.- DRAIN 3.- SOURCE

#### IGBTs, CoPACK

1.- GATE

2. 4.- COLLECTOR

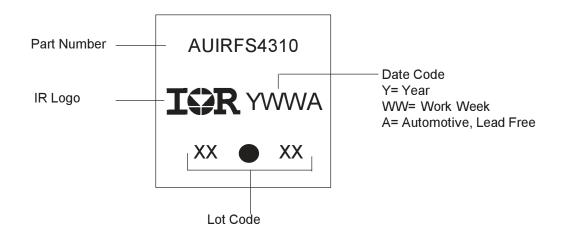
3.- EMITTER

#### DIODES

1.- ANODE \*
2, 4.- CATHODE
3.- ANODE

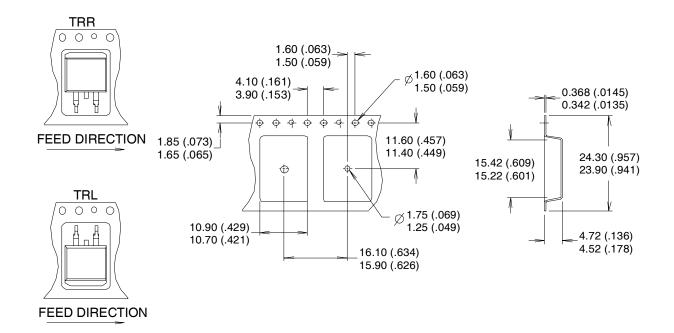
\* PART DEPENDENT.

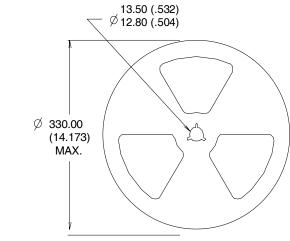
# D<sup>2</sup>Pak (TO-263AB) Part Marking Information

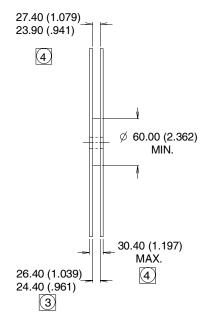


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

# D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information







## NOTES:

- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3 DIMENSION MEASURED @ HUB.
- 4 INCLUDES FLANGE DISTORTION @ OUTER EDGE.

**Ordering Information** 

Base part number	Package Type	Standard Pack	Complete Part Number	
		Form	Quantity	
AUIRFSL4310	TO-262	Tube	50	AUIRFSL4310
AUIRFS4310	D2Pak	Tube	50	AUIRFS4310
		Tape and Reel Left	800	AUIRFS4310TRL
		Tape and Reel Right	800	AUIRFS4310TRR



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For technical support, please contact IR's Technical Assistance Center

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